

Notice of References Cited	Application Control No	Applicant(s) Patent Under Reexamination	
	09 628 116	SOBCLEWSKI, ET AL	
Examiner	Art Unit	2878	Page 1 of 1
Timothy J. Moran			

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM YYYY	Name	Classification
A	US-			
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C	US-			
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E	US-			
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NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title, Date, Publisher, Edition or Volume, Pertinent Pages.
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Priority, if applicable, is being claimed with respect to: (1) U.S. MPEP § 1.38

Dates: MM YYYY, if applicable, (2) U.S. MPEP § 1.38